

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/038,943	NALLUR ET AL.	
Examiner	Art Unit	
Daniel Tekle	2621	

SEARCHED						
Class	Subclass	Date	Examiner			
386	68	8/1/2006	DT			
386	46	8/1/2006	DT			
386	86	8/1/2006	DT			
			-			

	INTERFERENCE SEARCHED					
Subclass	Date	Examiner				
	Subclass	Subclass Date				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East data base (I or B or P) adj3 (frame\$1 or picture\$1) same (trick or fast or high) near3 (speed or reproduc\$4) same (memor	8/3/2006	DT	
NPL (ACM digital library) PLUS Inventer search	8/1/2006	dt	
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	8/1/2006	DT	
Boccio Vincent	8/3/2006	DT	